

Notice of References Cited		Application/Control No. 10/561,799	Applicant(s)/Patent Under Reexamination OYAMA ET AL.	
		Examiner Stephen F. Gerrity	Art Unit 3721	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,788,448 A	08-1998	Wakamori et al.	414/939
*	B	US-6,186,331 B1	02-2001	Kinpara et al.	206/711
*	C	US-2001/0014267 A1	08-2001	YAMAGA et al.	414/217
*	D	US-6,302,927 B1	10-2001	Tanigawa, Osamu	414/217
*	E	US-6,398,475 B1	06-2002	Ishikawa, Toshio	414/217
*	F	US-2002/0106267 A1	08-2002	Fujii et al.	414/217
*	G	US-6,869,263 B2	03-2005	Gilchrist, Ulysses	414/217
*	H	US-2005/0111943 A1	05-2005	Otaguro, Tetsunori	414/411
*	I	US-6,984,097 B1	01-2006	Saeki et al.	414/411
*	J	US-6,984,839 B2	01-2006	Igarashi et al.	414/416.03
*	K	US-2003/0031537	02-2003	Tokunaga, Kenji	414/217
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 10335406 A	12-1998	Japan	YAMAOKA et al.	H01L 21/68
	O	JP 2003007801 A	01-2003	Japan	TATENO et al.	H01L 21/68
	P	JP 6-302679 A	10-1994	Japan	IWAI et al.	H01L 21/68
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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